

Search Notes

Application/Control No.

10/622,029

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

TAKIZAWA ET AL.

Art Unit

2176

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 715 | 523 | 8/10/2005 | |
| 707 | 200 | 8/10/2005 | |
| 717 | 114 | 8/10/2005 | |
| 709 | 204 | 8/10/2005 | |
| 715 | 511 | 1/31/2006 | |
| 707 | 1 | 1/31/2006 | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| INVENTORS SEARCH CHECK FOR DOUBLE PATENT | 8/10/2005 | |
| EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB See Search Histoty Printout | 8/10/2005 | |
| EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB See Search Histoty Printout | 1/31/2006 | |
| ACM DataBase See Search Histoty Printout | 1/31/2006 | |
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